Notice of References Cited Application/Control No. 10/587,857 Examiner Sean Basquill Applicant(s)/Patent Under Reexamination TAISHI ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2006/0128669	06-2006	Murai et al.	514/081
*	В	US-7,358,249	04-2008	Murai et al.	514/234.5
	O	US-			
	D	US-			
	Е	US-			
	F	US-			
	O	US-			
	Ι	US-		1	
	_	US-			
	7	US-			
	K	US-			
	Ш	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO2004/024693	03-2004	JP	Murai	C07D 215/48
	0					
	Р					
	Q					
	R					
	s					
	-1			2424346		

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.